

MODEL 160



Specimen Grinder

Produce uniform thickness specimens
with parallel sides



MODEL 160

Specimen Grinder

Mechanically prethins specimens for transmission electron microscopy (TEM). Greatly reduces the time spent during the final preparation process of ion beam milling.

- **Accurate and dependable**
- **Precisely controlled**
- **Specimens up to 18 mm diameter**
- **Excellent stability**
- **No additional force needed**
- **Large diameter provides excellent stability**
- **Consistently produce specimens with uniform thickness and parallel sides**
- **Platen transferable to the Fischione Model 200 Dimpling Grinder**

SPECIMEN GRINDING

For transmission electron microscopy (TEM), the quality of the initial disk determines the quality of the final specimen. The disk can be mechanically ground using the Model 160 Specimen Grinder to a precisely controlled thickness. Use the Fischione Model 200 Dimpling Grinder for final thinning.



Mechanically prethin specimens

The Model 160 Specimen Grinder is an accurate and dependable tool for mechanically prethinning specimens in preparation for transmission electron microscopy (TEM). The grinder accommodates up to 18 mm diameter specimens.

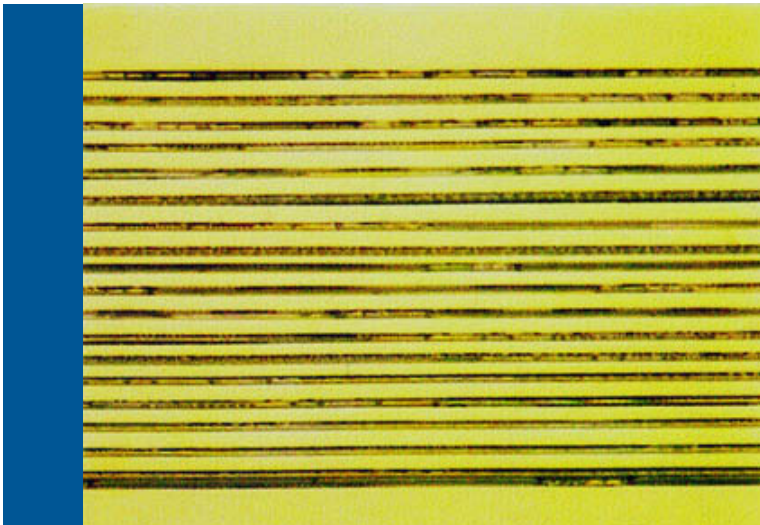
The specimen grinder greatly reduces the time spent during the final preparation process of ion beam milling, which is typically used to achieve electron transparency.

A graduated scale allows the specimen thickness to be easily and precisely controlled; rotating the control knob advances the specimen 0.5 mm per rotation.

The large diameter provides excellent stability. Specimens with uniform thickness and parallel sides are consistently produced because of the precise fit of the specimen platen into the grinder body. The grinder is heavy enough to provide sufficient grinding force on the specimen.

One-step mounting

If further thinning via dimpling is required, the platen containing the specimen is simply ejected from the specimen grinder and installed directly into the Fischione Model 200 Dimpling Grinder. This eliminates any possibility of damaging the specimen by demounting it for dimpling.



Optical image of an XTEM specimen consisting of 19 individual sections of a microelectronic material. Produced by ultrasonic disk cutting and mechanical grinding.



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